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| Notice of References Cited | Application/Control No. 10/551,973 | | Applicant(s)/Patent Under Reexamination VAN DE KERKHOFF ET AL. | |
| | Examiner MOHAMMAD W. REZA | | Art Unit 2436 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-7,047,187 | 05-2006 | Cheng et al. | 704/219 |
| * | B | US-7,046,808 | 05-2006 | Metois et al. | 380/252 |
| * | C | US-7,228,425 | 06-2007 | Staring et al. | 713/176 |
| * | D | US-2001/0054144 | 12-2001 | Epstein et al. | 713/161 |
| * | E | US-7,072,718 | 07-2006 | Von Arx et al. | 607/60 |
| * | F | US-7,266,704 | 09-2007 | Levy, Kenneth L. | 713/193 |
| * | G | US-7,277,468 | 10-2007 | Tian et al. | 375/130 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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